

FDC2x1x Multi-Channel, High Resolution Capacitance-to-Digital Converter for Capacitive Sensing Applications

1 Features

- EMI-resistant architecture
- Maximum output rates (one active channel):
	- 13.3kSPS (FDC2112, FDC2114)
	- 4.08kSPS (FDC2212, FDC2214)
- Maximum input capacitance: 250nF (at 10kHz with 1mH inductor)
- Sensor excitation frequency: 10kHz to 10MHz
- Number of channels: 2, 4
- Resolution: up to 28 bits
- System noise floor: 0.3fF at 100SPS
- Supply voltage: 2.7V to 3.6V
- Power consumption: active: 2.1mA
- Low-power sleep mode: 35µA
- Shutdown: 200nA
- Interface: $I²C$
- Temperature range: -40°C to +125°C

2 Applications

- Proximity sensor
- Gesture recognition
- Level sensor for liquids, including conductive ones such as detergent, soap, and ink

3 Description

Capacitive sensing is a low-power, high-resolution contactless sensing technique that can be applied to a variety of applications ranging from proximity detection and gesture recognition to remote liquid level sensing. The sensor in a capacitive sensing system is any metal or conductor, allowing for a highly flexible system design.

The main challenge limiting sensitivity in capacitive sensing applications is noise susceptibility of the sensors. With the FDC2x1x resonant sensing architecture, performance can be maintained even in the presence of fluorescent light.

The FDC2x1x is a multi-channel family of high-resolution, high-speed capacitance-to-digital converters for implementing capacitive sensing solutions. The devices employ an innovative narrowband based architecture to offer high rejection of out of band noise while providing high resolution at high speed. The devices support a wide excitation frequency range, offering flexibility in system design. A wide frequency range is especially useful for reliable sensing of conductive liquids such as detergent, soap, and ink.

The FDC221x is optimized for high resolution, up to 28 bits, while the FDC211x offers a fast sample rate of up to 13.3kSPS for easy implementation of applications that use fast moving targets. The large maximum input capacitance of 250nF allows for the use of remote sensors, as well as for tracking environmental changes over time such as temperature and humidity.

The FDC2x1x family targets proximity sensing and liquid level sensing applications for any type of liquids. For non-conductive liquid level sensing applications in the presence of interferences such as human hands, the FDC1004 is recommended and features integrated active shield drivers.

Package Information

(1) For all available packages, see [Section 11.](#page-49-0)

 (2) The package size (length \times width) is a nominal value and includes pins, where applicable.

Simplified Schematic

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4 Device Comparison

Table 4-1. Device Comparison

5 Pin Configuration and Functions

Table 5-1. Pin Functions

Table 5-1. Pin Functions (continued)

(1) I = Input, O = Output, P=Power, G=Ground, A=Analog

(2) There is an internal electrical connection between the exposed Die Attach Pad (DAP) and the GND pin of the device. Although the DAP can be left floating, connect the DAP to the same potential as the GND pin of the device for best performance. Do not use the DAP as the primary ground for the device. The device GND pin must always be connected to ground.

6 Specifications

6.1 Absolute Maximum Ratings

See (1)

(1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

(1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

Unless otherwise specified, all limits ensured for $T_A = 25^{\circ}$ C, VDD = 3.3V

6.4 Thermal Information

(1) For more information about traditional and new thermal metrics, see the *[Semiconductor and IC Package Thermal Metrics](https://www.ti.com/lit/pdf/spra953)* application note.

6.5 Electrical Characteristics

(1) *Electrical Characteristics* values apply only for factory testing conditions at the temperature indicated. Factory testing conditions result in very limited self-heating of the device such that T $_{\rm J}$ = T_A. No guarantee of parametric performance is indicated in the electrical tables under conditions of internal self-heating where T_J > T_A. *Absolute Maximum Ratings* indicate junction temperature limits beyond which the device can be permanently degraded, either mechanically or electrically.

(2) Register values are represented as either binary (b is the prefix to the digits), or hexadecimal (0x is the prefix to the digits). Decimal values have no prefix.

(3) Limits are ensured by testing, design, or statistical analysis at 25°C. Limits over the operating temperature range are ensured through correlations using statistical quality control (SQC) method.

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- (4) Typical values represent the most likely parametric norm as determined at the time of characterization. Actual typical values can vary over time and also depend on the application and configuration. The typical values are not tested and are not ensured on shipped production material.
- (5) 1²C read/write communication and pullup resistors current through SCL, SDA not included.
- (6) Sensor capacitor: 1 layer, 20.9 x 13.9mm, Bourns CMH322522-180KL sensor inductor with L=18µH and 33pF 1% COG/NP0 Target: Grounded aluminum plate (176 x 123mm), Channel = Channel 0 (continuous mode) CLKIN = 40MHz, CHx FIN_SEL = b10, CHx_FREF_DIVIDER = b00 0000 0001 CH0_RCOUNT = 0xFFFF, SETTLECOUNT CH0 = 0x0100, DRIVE_CURRENT_CH0 = 0x7800.
- (7) Lower V_{SENSORMIN} oscillation amplitudes can be used, but will result in lower SNR.

6.6 Timing Requirements

Figure 6-1. I ²C Timing

6.7 Switching Characteristics - I2C

Unless otherwise specified, all limits ensured for $T_A = 25^{\circ}$ C, VDD = 3.3V

(1) This parameter is specified by design and/or characterization and is not tested in production.

6.8 Typical Characteristics

Common test conditions (unless specified otherwise): Sensor capacitor: 1 layer, 20.9mm × 13.9mm, Bourns CMH322522-180KL sensor inductor with L=18µH and 33pF 1% COG/NP0 Target: Grounded aluminum plate (176mm × 123mm), Channel = Channel 0 (continuous mode) CLKIN = 40MHz, CHx_FIN_SEL = b01, CHx_FREF_DIVIDER = b00 0000 0001 CH0_RCOUNT = 0xFFFF, SETTLECOUNT_CH0 = 0x0100, DRIVE_CURRENT_CH0 = 0x7800.

6.8 Typical Characteristics (continued)

Common test conditions (unless specified otherwise): Sensor capacitor: 1 layer, 20.9mm × 13.9mm, Bourns CMH322522-180KL sensor inductor with L=18µH and 33pF 1% COG/NP0 Target: Grounded aluminum plate (176mm × 123mm), Channel = Channel 0 (continuous mode) CLKIN = 40MHz, CHx FIN_SEL = b01, CHx_FREF_DIVIDER = b00 0000 0001 CH0_RCOUNT = 0xFFFF, SETTLECOUNT_CH0 = 0x0100, DRIVE_CURRENT_CH0 = 0x7800.

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7 Detailed Description

7.1 Overview

The FDC2112, FDC2114, FDC2212, and FDC2214 are high-resolution, multichannel capacitance-to-digital converters for implementing capacitive sensing solutions. In contrast to traditional switched-capacitance architectures, the FDC2112, FDC2114, FDC2212, and FDC2214 employ an L-C resonator, also known as L-C tank, as a sensor. The narrow-band architecture allows unprecedented EMI immunity and greatly reduced noise floor when compared to other capacitive sensing solutions.

Using this approach, a change in capacitance of the L-C tank can be observed as a shift in the resonant frequency. Using this principle, the FDC is a capacitance-to-digital converter (FDC) that measures the oscillation frequency of an LC resonator. The device outputs a digital value that is proportional to frequency. This frequency measurement can be converted to an equivalent capacitance

7.2 Functional Block Diagrams

Figure 7-1. Block Diagram for the FDC2112 and FDC2212

Figure 7-2. Block Diagrams for the FDC2114 and FDC2214

The FDC is composed of front-end resonant circuit drivers, followed by a multiplexer that sequences through the active channels, connecting them to the core that measures and digitizes the sensor frequency (f_{SENSOR}). The core uses a reference frequency (f_{REF}) to measure the sensor frequency. f_{REF} is derived from either an internal reference clock (oscillator), or an externally supplied clock. The digitized output for each channel is proportional to the ratio of $f_{\text{SENSOR}}/f_{\text{REF}}$. The I²C interface is used to support device configuration and to transmit the digitized frequency values to a host processor. The FDC can be placed in shutdown mode, saving current, using the SD pin. The INTB pin can be configured to notify the host of changes in system status.

7.3 Feature Description

7.3.1 Clocking Architecture

Figure 7-3 shows the clock dividers and multiplexers of the FDC.

A. FDC2114 / FDC2214 only

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Figure 7-3. Clocking Diagram

In Figure 7-3, the key clocks are f_{IN} , f_{REF} , and f_{CLK} . f_{CLK} is selected from either the internal clock source or external clock source (CLKIN). The frequency measurement reference clock, f_{REF} , is derived from the f_{CLK} source. TI recommends that precision applications use an external controller clock that offers the stability and accuracy requirements needed for the application. The internal oscillator can be used in applications that require low cost and do not require high precision. The f_{INX} clock is derived from sensor frequency for a channel x, f_{SENSORx} . f_{REFx} and f_{INx} must meet the requirements listed in [Table 7-1](#page-12-0), depending on whether f_{CLK} (controller clock) is the internal or external clock.

Table 7-1. Clock Configuration Requirements

(1) Channels 2 and 3 are only available for FDC2114 and FDC2214.

(2) Refer to *[Sensor Configuration](#page-38-0)* for information on differential and single-ended sensor configurations.

Table 7-2 shows the clock configuration registers for all channels.

(1) Channels 2 and 3 are only available for FDC2114 and FDC2214

7.3.2 Multi-Channel and Single-Channel Operation

The multi-channel package of the FDC enables the user to save board space and support flexible system design. For example, temperature drift can often cause a shift in component values, resulting in a shift in resonant frequency of the sensor. Using a second sensor as a reference provides the capability to cancel out a temperature shift. When operated in multi-channel mode, the FDC sequentially samples the active channels. In single-channel mode, the FDC samples a single channel, which is selectable. [Table 7-3](#page-13-0) shows the registers and values that are used to configure either multi-channel or single-channel modes.

Table 7-3. Single- and Multi-Channel Configuration Registers

The digitized sensor measurement for each channel (DATAx) represents the ratio of the sensor frequency to the reference frequency.

The data output (DATAx) of the FDC2112 and FDC2114 is expressed as the 12 MSBs of a 16-bit result:

$$
DATA_x = \frac{f_{\text{SENSORx}} * 2^{12}}{f_{\text{REFx}}} \tag{1}
$$

The data output (DATAx) of the FDC2212 and FDC2214 is expressed as:

Table 7-4 illustrates the registers that contain the fixed point sample values for each channel.

Table 7-4. Sample Data Registers

Table 7-4. Sample Data Registers (continued)

(1) The DATA_CHx.DATAx register must always be read first, followed by the DATA_LSB_ CHx.DATAx register of the same channel to ensure data coherency.

(2) Channels 2 and 3 are only available for FDC2114 and FDC2214.

(3) A DATA value of 0x0000000 = under range for FDC2212/FDC2214.

(4) A DATA value of 0xFFFFFFF = over range for FDC2212/FDC2214.

When the FDC sequences through the channels in multi-channel mode, the dwell time interval for each channel is the sum of three parts:

1. sensor activation time

- 2. conversion time
- 3. channel switch delay

The sensor activation time is the amount of settling time required for the sensor oscillation to stabilize, as shown in Figure 7-4. The settling wait time is programmable, and TI recommends setting the wait time to a value that is long enough to allow stable oscillation. The settling wait time for channel x is given by:

 t_{Sx} = (CHX_SETTLECOUNT×16)/f_{REFx} (3)

[Table 7-5](#page-15-0) illustrates the registers and values for configuring the settling time for each channel.

Figure 7-5. Single-Channel Mode Sequencing

Table 7-5. Settling Time Register Configuration

(1) Channels 2 and 3 are available only in the FDC2114 and FDC2214.

 (2) f_{REFx} is the reference frequency configured for the channel.

The SETTLECOUNT for any channel x must satisfy:

- CHx_SETTLECOUNT > V_{pk} × f_{REFx} × C × π² / (32 × IDRIVE_X) (4)
- – where
	- $-V_{\text{pk}}$ = Peak oscillation amplitude at the programmed IDRIVE setting
	- $-$ f_{REFx} = Reference frequency for Channel x
	- C = sensor capacitance including parasitic PCB capacitance
	- $-$ IDRIVE_X = setting programmed into the IDRIVE register in amps
- Round the result to the next highest integer (for example, if Equation 4 recommends a minimum value of 6.08, program the register to 7 or higher).
- The conversion time represents the number of reference clock cycles used to measure the sensor frequency and is set by the CHx_RCOUNT register for the channel. The conversion time for any channel x is:
- $t_{Cx} = (CHx \ RCOUNT \times 16 + 4) /f_{REFx}$ (5)
- The reference count value must be chosen to support the required number of effective bits (ENOB). For example, if an ENOB of 13 bits is required, then a minimum conversion time of 2^{13} = 8192 clock cycles is required. 8192 clock cycles correspond to a CHx_RCOUNT value of 0x0200.

Table 7-6. Conversion Time Configuration Registers, Channels 0 - 3 (1)

(1) Channels 2 and 3 are available only for FDC2114 and FDC2214.

The typical channel switch delay time between the end of conversion and the beginning of sensor activation of the subsequent channel is:

$$
Channel Switch Delay = 692ns + 5 / f_{ref}
$$
\n(6)

The deterministic conversion time of the FDC allows data polling at a fixed interval. For example, if the programmed RCOUNT setting is 512 F_{REF} cycles and SETTLECOUNT is 128 F_{REF} cycles, then one conversion takes 1.8ms (sensor-activation time) + 3.2ms (conversion time) + 0.75ms (channel-switch delay) = 16.75ms per channel. If the FDC is configured for dual-channel operation by setting AUTOSCAN_EN = 1 and RR SEQUENCE = 00, then one full set of conversion results are available from the data registers every 33.5ms.

A data ready flag (DRDY) is also available for interrupt driven system designs (see the STATUS register description in *[Register Maps](#page-20-0)*).

7.3.3 Gain and Offset (FDC2112, FDC2114 Only)

The FDC2112 and FDC2114 have internal 16-bit data converters, but the standard conversion output word width is only 12 bits; therefore only 12 of the 16 bits are available from the data registers. By default, the gain feature is disabled and the DATA registers contain the 12 MSBs of the 16-bit word. However, it is possible to shift the data

output by up to 4 bits. Figure 7-6 illustrates the segment of the 16-bit sample that is reported for each possible gain setting.

Figure 7-6. Conversion Data Output Gain

For systems in which the sensor signal variation is less than 25% of the full-scale range, the FDC can report conversion results with higher resolution by setting the Output Gain. The Output Gain is applied to all device channels. An output gain can be used to apply a 2-bit, 3-bit, or 4-bit shift to the output code for all channels, allowing access to the 4 LSBs of the original 16-bit result. The MSBs of the sample are shifted out when a gain is applied. Do not use the output gain if the MSBs of any active channel are toggling, as the MSBs for that channel are lost when gain is applied.

Example: If the conversion result for a channel is 0x07A3, with OUTPUT GAIN=0x0, the reported output code is 0x07A. If OUTPUT GAIN is set to 0x3 in the same condition, then the reported output code is 0x7A3. The original 4 MSBs (0x0) are no longer accessible.

Table 7-7. Output Gain Register (FDC2112 and FDC2114 Only)

(1) Channels 2 and 3 are available for FDC2114 only.

An offset value can be subtracted from each DATA value to compensate for a frequency offset or maximize the dynamic range of the sample data. Make sure the offset values \lt f_{SENSORx} MIN / fREFx. Otherwise, the offset might be so large that the offset masks the LSBs which are changing.

[FDC2212,](https://www.ti.com/product/FDC2212) [FDC2214](https://www.ti.com/product/FDC2214), [FDC2112](https://www.ti.com/product/FDC2112), [FDC2114](https://www.ti.com/product/FDC2114) [SNOSCZ5B](https://www.ti.com/lit/pdf/SNOSCZ5) – JUNE 2015 – REVISED OCTOBER 2024 **www.ti.com**

Table 7-8. Frequency Offset Registers

(1) Channels 2 and 3 are only available for FDC2114 and FDC2214.

The sensor capacitance C_{SENSE} of a differential sensor configuration can be determined by:

$$
C_{\text{SENSOR}} = \frac{1}{L * (2\pi * f_{\text{SENSORx}})^2} - C
$$
\n(7)

where

• C = parallel sensor capacitance (see [Figure 8-2](#page-38-0))

The FDC2112 and FDC2114 sensor frequency $f_{\text{SENSOR}x}$ can be determined by:

$$
f_{\text{SENSORx}} = \text{CHx_FIN_SEL} * f_{\text{REFx}} * \left(\frac{\text{DATAx}}{2^{(12+ \text{OUTPUT_GAIN})}} + \frac{\text{CHx}_{\text{OFFSET}}}{2^{16}} \right)
$$
(8)

where

- DATAx = Conversion result from the DATA_CHx register
- CHx_OFFSET = Offset value set in the OFFSET_CHx register
- OUTPUT_GAIN = output multiplication factor set in the RESET_DEVICE.OUTPUT_GAIN register

The FDC2212 and FDC2214 sensor frequency f_{SENSORx} can be determined by:

$$
f_{\text{SENSORx}} = \frac{\text{CHx_FIN_SEL} * f_{\text{REFx}} * \text{DATAx}}{2^{28}} \quad \text{(FDC2212, FDC2214)} \tag{9}
$$

where

• DATAx = Conversion result from the DATA_CHx register

7.3.4 Current Drive Control Registers

The registers listed in Table 7-9 are used to control the sensor drive current. Follow the recommendations listed in the last column of the table.

CHANNEL ⁽¹⁾	REGISTER	FIELD [BIT(S)]	VALUE
All	CONFIG, addr 0x1A	SENSOR ACTIVATE SEL [11]	Sets current drive for sensor activation. Recommended value is b0 (Full Current mode).
0	CONFIG, addr 0x1A	HIGH CURRENT DRV [6]	$ b0$ = normal current drive (1.5mA) $b1$ = Increased current drive (> 1.5 mA) for Ch 0 in single channel mode only. Cannot be used in multi-channel mode.
0	DRIVE CURRENT CHO, addr 0x1E CHO IDRIVE [15:11]		Drive current used during the settling and conversion time for Ch. 0. Set such that 1.2V ≤ sensor oscillation amplitude (pk) $≤$ 1.8V

Table 7-9. Current Drive Control Registers

Table 7-9. Current Drive Control Registers (continued)

(1) Channels 2 and 3 are available for FDC2114 and FDC2214 only.

The CHx IDRIVE field should be programmed such that the sensor oscillates at an amplitude between 1.2Vpk (V_{SENSORMIN}) and 1.8Vpk (V_{SENSORMAX}). An IDRIVE value of 00000 corresponds to 16µA, and IDRIVE = b11111 corresponds to 1563µA.

A high sensor current drive mode can be enabled to drive sensor coils with > 1.5mA on channel 0, only in single channel mode. This feature can be used when the sensor minimum recommended oscillation amplitude of 1.2V cannot be achieved with the highest IDRIVE setting. Set the HIGH_CURRENT_DRV register bit to b1 to enable this mode.

7.3.5 Device Status Registers

The registers listed in Table 7-10 can be used to read device status.

Table 7-10. Status Registers

(1) Channels 2 and 3 are available for FDC2114 and FDC2114 only.

See the STATUS and STATUS CONFIG register description in the Register Map section. These registers can be configured to trigger an interrupt on the INTB pin for certain events. The following conditions must be met:

- 1. The error or status register must be unmasked by enabling the appropriate register bit in the STATUS_CONFIG register
- 2. The INTB function must be enabled by setting CONFIG.INTB DIS to 0

When a bit field in the STATUS register is set, the entire STATUS register content is held until read or until the DATA_CHx register is read. Reading also deasserts INTB.

Interrupts are cleared by one of the following events:

- 1. Entering Sleep Mode
- 2. Power-on reset (POR)
- 3. Device enters Shutdown Mode (SD is asserted)
- 4. S/W reset
- 5. I²C read of the STATUS register: Reading the STATUS register clears any error status bit set in STATUS along with the ERR_CHAN field and deassert INTB

Setting register CONFIG.INTB_DIS to b1 disables the INTB function and holds the INTB pin high.

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7.3.6 Input Deglitch Filter

The input deglitch filter suppresses EMI and ringing above the sensor frequency. The input deglitch filter does not impact the conversion result as long as the bandwidth is configured to be above the maximum sensor frequency. The input deglitch filter can be configured in MUX CONFIG.DEGLITCH register field as shown in Table 7-11. For optimal performance, TI recommends to select the lowest setting that exceeds the sensor oscillation frequency. For example, if the maximum sensor frequency is 2.0MHz, choose MUX CONFIG.DEGLITCH = $b100$ (3.3MHz).

Table 7-11. Input Deglitch Filter Register

(1) Channels 2 and 3 are available for FDC2114 / FDC2214 only.

7.4 Device Functional Modes

7.4.1 Start-Up Mode

When the FDC powers up, the FDC enters into Sleep Mode and waits for configuration. When the device is configured, exit Sleep Mode by setting CONFIG.SLEEP_MODE_EN to b0.

TI recommends to configure the FDC while in Sleep Mode. If a setting on the FDC needs to be changed, return the device to Sleep Mode, change the appropriate register, and then exit Sleep Mode.

7.4.2 Normal (Conversion) Mode

When operating in the normal (conversion) mode, the FDC is periodically sampling the frequency of the sensor(s) and generating sample outputs for the active channel(s).

7.4.3 Sleep Mode

Sleep Mode is entered by setting the CONFIG.SLEEP MODE EN register field to 1. While in this mode, the register contents are maintained. To exit Sleep Mode, set the CONFIG.SLEEP MODE EN register field to 0. After setting CONFIG.SLEEP_MODE_EN to b0, sensor activation for the first conversion begins after 16,384 f_{INT} clock cycles. While in Sleep Mode the 12 C interface is functional so that register reads and writes can be performed. While in Sleep Mode, no conversions are performed. In addition, entering Sleep Mode clears any error condition and deassert the INTB pin.

7.4.4 Shutdown Mode

When the SD pin is set to high, the FDC enters Shutdown Mode. Shutdown Mode is the lowest power state. To exit Shutdown Mode, set the SD pin to low. Entering Shutdown Mode returns all registers to the default states.

While in Shutdown Mode, no conversions are performed. In addition, entering Shutdown Mode clears any error condition and deassert the INTB pin. While the device is in Shutdown Mode, is not possible to read to or write from the device via the I2C interface.

7.4.4.1 Reset

The FDC can be reset by writing to RESET_DEV.RESET_DEV. Conversion stops and all register values return to the default values. This register bit always returns 0b when read.

7.5 Programming

The FDC device uses an I²C interface to access control and data registers.

7.5.1 I ²C Interface Specifications

The FDC uses an extended start sequence with I²C for register access. The maximum speed of the I²C interface is 400kbps. This sequence follows the standard $I²C$ 7-bit target address followed by an 8-bit pointer register byte

to set the register address. When the ADDR pin is set low, the FDC I²C address is 0x2A; when the ADDR pin is set high, the FDC I²C address is 0x2B. The ADDR pin must not change state after the FDC exits Shutdown Mode.

Figure 7-8. I ²C Read Register Sequence

7.6 Register Maps

7.6.1 Register List

Fields indicated with Reserved must be written only with indicated values. Improper device operation can occur otherwise. The R/W column indicates the Read-Write status of the corresponding field. A 'R/W' entry indicates read and write capability, a 'R' indicates read-only, and a 'W' indicates write-only.

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Figure 7-9. Register List (continued)

7.6.2 Address 0x00, DATA_CH0

Table 7-12. Address 0x00, DATA_CH0 Field Descriptions

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Table 7-12. Address 0x00, DATA_CH0 Field Descriptions (continued)

7.6.3 Address 0x01, DATA_LSB_CH0 (FDC2212 / FDC2214 only)

Table 7-13. Address 0x01, DATA_CH0 Field Descriptions

7.6.4 Address 0x02, DATA_CH1

Figure 7-12. Address 0x02, DATA_CH1

Table 7-14. Address 0x02, DATA_CH1 Field Descriptions

7.6.5 Address 0x03, DATA_LSB_CH1 (FDC2212 / FDC2214 only)

Figure 7-13. Address 0x03, DATA_LSB_CH1

Table 7-15. Address 0x03, DATA_CH1 Field Descriptions

7.6.6 Address 0x04, DATA_CH2 (FDC2114, FDC2214 only)

Table 7-16. Address 0x04, DATA_CH2 Field Descriptions

7.6.7 Address 0x05, DATA_LSB_CH2 (FDC2214 only)

Figure 7-15. Address 0x05, DATA_LSB_CH2

Table 7-17. Address 0x05, DATA_CH2 Field Descriptions

7.6.8 Address 0x06, DATA_CH3 (FDC2114, FDC2214 only)

Figure 7-16. Address 0x06, DATA_CH3

Table 7-18. Address 0x06, DATA_CH3 Field Descriptions

Table 7-18. Address 0x06, DATA_CH3 Field Descriptions (continued)

7.6.9 Address 0x07, DATA_LSB_CH3 (FDC2214 only)

Table 7-19. Address 0x07, DATA_CH3 Field Descriptions

7.6.10 Address 0x08, RCOUNT_CH0

Table 7-20. Address 0x08, RCOUNT_CH0 Field Descriptions

7.6.11 Address 0x09, RCOUNT_CH1

Figure 7-19. Address 0x09, RCOUNT_CH1

Table 7-21. Address 0x09, RCOUNT_CH1 Field Descriptions

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7.6.12 Address 0x0A, RCOUNT_CH2 (FDC2114, FDC2214 only)

Figure 7-20. Address 0x0A, RCOUNT_CH2

Table 7-22. Address 0x0A, RCOUNT_CH2 Field Descriptions

7.6.13 Address 0x0B, RCOUNT_CH3 (FDC2114, FDC2214 only)

Table 7-23. Address 0x0B, RCOUNT_CH3 Field Descriptions

7.6.14 Address 0x0C, OFFSET_CH0 (FDC21112 / FDC2114 only)

Table 7-24. CH0_OFFSET Field Descriptions

7.6.15 Address 0x0D, OFFSET_CH1 (FDC21112 / FDC2114 only)

Table 7-25. Address 0x0D, OFFSET_CH1 Field Descriptions

7.6.16 Address 0x0E, OFFSET_CH2 (FDC2114 only)

Figure 7-24. Address 0x0E, OFFSET_CH2

Table 7-26. Address 0x0E, OFFSET_CH2 Field Descriptions

7.6.17 Address 0x0F, OFFSET_CH3 (FDC2114 only)

Figure 7-25. Address 0x0F, OFFSET_CH3

Table 7-27. Address 0x0F, OFFSET_CH3 Field Descriptions

7.6.18 Address 0x10, SETTLECOUNT_CH0

Figure 7-26. Address 0x10, SETTLECOUNT_CH0

Table 7-28. Address 0x11, SETTLECOUNT_CH0 Field Descriptions

7.6.19 Address 0x11, SETTLECOUNT_CH1

Figure 7-27. Address 0x11, SETTLECOUNT_CH1

Table 7-29. Address 0x12, SETTLECOUNT_CH1 Field Descriptions

7.6.20 Address 0x12, SETTLECOUNT_CH2 (FDC2114, FDC2214 only)

Table 7-30. Address 0x12, SETTLECOUNT_CH2 Field Descriptions

7.6.21 Address 0x13, SETTLECOUNT_CH3 (FDC2114, FDC2214 only)

Figure 7-29. Address 0x13, SETTLECOUNT_CH3

Table 7-31. Address 0x13, SETTLECOUNT_CH3 Field Descriptions

7.6.22 Address 0x14, CLOCK_DIVIDERS_CH0

Figure 7-30. Address 0x14, CLOCK_DIVIDERS_CH0

Table 7-32. Address 0x14, CLOCK_DIVIDERS_CH0 Field Descriptions

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Table 7-32. Address 0x14, CLOCK_DIVIDERS_CH0 Field Descriptions (continued)

7.6.23 Address 0x15, CLOCK_DIVIDERS_CH1

Figure 7-31. Address 0x15, CLOCK_DIVIDERS_CH1

Table 7-33. Address 0x15, CLOCK_DIVIDERS_CH1 Field Descriptions

7.6.24 Address 0x16, CLOCK_DIVIDERS_CH2 (FDC2114, FDC2214 only)

Figure 7-32. Address 0x16, CLOCK_DIVIDERS_CH2

Table 7-34. Address 0x16, CLOCK_DIVIDERS_CH2 Field Descriptions

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Table 7-34. Address 0x16, CLOCK_DIVIDERS_CH2 Field Descriptions (continued)

7.6.25 Address 0x17, CLOCK_DIVIDERS_CH3 (FDC2114, FDC2214 only)

Figure 7-33. Address 0x17, CLOCK_DIVIDERS_CH3

Table 7-35. Address 0x17, CLOCK_DIVIDERS_CH3

7.6.26 Address 0x18, STATUS

Figure 7-34. Address 0x18, STATUS

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Table 7-36. Address 0x18, STATUS Field Descriptions

7.6.27 Address 0x19, ERROR_CONFIG

Table 7-37. Address 0x19, ERROR_CONFIG

7.6.28 Address 0x1A, CONFIG

Figure 7-36. Address 0x1A, CONFIG

Table 7-38. Address 0x1A, CONFIG Field Descriptions

7.6.29 Address 0x1B, MUX_CONFIG

Figure 7-37. Address 0x1B, MUX_CONFIG

Table 7-39. Address 0x1B, MUX_CONFIG Field Descriptions

Table 7-39. Address 0x1B, MUX_CONFIG Field Descriptions (continued)

7.6.30 Address 0x1C, RESET_DEV

Figure 7-38. Address 0x1C, RESET_DEV

Table 7-40. Address 0x1C, RESET_DEV Field Descriptions

7.6.31 Address 0x1E, DRIVE_CURRENT_CH0

Figure 7-39. Address 0x1E, DRIVE_CURRENT_CH0

Table 7-41. Address 0x1E, DRIVE_CURRENT_CH0 Field Descriptions

7.6.32 Address 0x1F, DRIVE_CURRENT_CH1

Table 7-42. Address 0x1F, DRIVE_CURRENT_CH1 Field Descriptions

Table 7-42. Address 0x1F, DRIVE_CURRENT_CH1 Field Descriptions (continued)

7.6.33 Address 0x20, DRIVE_CURRENT_CH2 (FDC2114 / FDC2214 only)

Figure 7-41. Address 0x20, DRIVE_CURRENT_CH2

Table 7-43. Address 0x20, DRIVE_CURRENT_CH2 Field Descriptions

7.6.34 Address 0x21, DRIVE_CURRENT_CH3 (FDC2114 / FDC2214 only)

Figure 7-42. Address 0x21, DRIVE_CURRENT_CH3

Table 7-44. DRIVE_CURRENT_CH3 Field Descriptions

7.6.35 Address 0x7E, MANUFACTURER_ID

Figure 7-43. Address 0x7E, MANUFACTURER_ID

Table 7-45. Address 0x7E, MANUFACTURER_ID Field Descriptions

7.6.36 Address 0x7F, DEVICE_ID

Figure 7-44. Address 0x7F, DEVICE_ID

Table 7-46. Address 0x7F, DEVICE_ID Field Descriptions

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

8.1.1 Sensor Configuration

The FDC supports two sensor configurations. Both configurations use an LC tank to set the frequency of oscillation. A typical choice is an 18 μH shielded SMD inductor in parallel with a 33pF capacitor, which result in a 6.5MHz oscillation frequency. In the single-ended configuration in Figure 8-1, a conductive plate is connected IN0A. Together with a target object, the conductive plate forms a variable capacitor.

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Figure 8-1. Single-Ended Sensor Configuration

In the differential sensor configuration in Figure 8-2, one conductive plate is connected to IN0A, and a second conductive plate is connected to IN0B. Together, they form a variable capacitor. When using an single-ended sensor configuration, set CHx_FIN_SEL to b10 (divide by 2).

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Figure 8-2. Differential Sensor Configuration

The single-ended configuration allows higher sensing range than the differential configuration for a given total sensor plate area. In applications in which high sensitivity at close proximity is desired, the differential configuration performs better than the single-ended configuration.

8.1.2 Shield

in order to minimize interference from external objects, some applications require an additional plate which acts as a shield. The shield can either be:

• actively driven shield: The shield is a buffered signal of the INxA pin. The signal is buffered by an external amplifier with a gain of 1.

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• passive shield: The shield is connected to GND. Adding a passive shield decreases sensitivity of the sensor, but is dependent on the distance between the distance between the sensing plate and the shield. Adjust the distance between the sensing plate and the shield to achieve the required sensitivity

8.1.3 Power-Cycled Applications

For applications which do not require high sample rates or maximum conversion resolution, the total active conversion time of the FDC can be minimized to reduce power consumption. This can be done by either by using sleep mode or shutdown mode during times in which conversions are not required (see *[Device Functional](#page-19-0) [Modes](#page-19-0)*).

As an example, for an application which only needs 10 samples per second with a resolution of 16 bits can utilize the low-power modes. The sensor requires SETTLECOUNT = 16 and IDRIVE of 01111b (0.146mA). Given FREF = 40MHz and RCOUNT = 4096 will provide the resolution required. This corresponds to 4096 * 16 * 10 / 40 MHz \rightarrow 16.4ms of active conversion time per second. Start-up time and channel switch delay account for an additional 0.34ms. For the remainder of the time, the device can be in sleep mode: Therefore, the average current is 19.4ms * 3.6mA active current + 980.6ms of 35µA of sleep current, which is approximately 104.6µA of average supply current. Sleep mode retains register settings and therefore requires less I²C writes to wake up the FDC than shutdown mode.

Greater current savings can be realized by use of shutdown mode during inactive periods. In shutdown mode, device configuration is not retained, and so the device must be configured for each sample. For this example, configuring each sample takes approximately 1.2ms (13 registers * 92.5 µs per register). The total active time is 20.6ms. The average current is 20ms * 3.6mA active current + 980ms * 2µA of shutdown current, which is approximately 75µA of average supply current.

8.1.4 Inductor Self-Resonant Frequency

Every inductor has a distributed parasitic capacitance, which is dependent on construction and geometry. At the Self-Resonant Frequency (SRF), the reactance of the inductor cancels the reactance of the parasitic capacitance. Above the SRF, the inductor electrically appears to be a capacitor. Because the parasitic capacitance is not well-controlled or stable, TI recommends that f_{SENSOR} < 0.8 \times f_{SR} .

Figure 8-3. Example Coil Inductance vs Frequency

The example inductor in Figure 8-3, has a SRF at 6.38MHz; therefore do not operate the inductor above 0.8×6.38MHz, or 5.1MHz.

8.1.5 Application Curves

Common test conditions (unless specified otherwise): Sensor capacitor: 1 layer, 20.9 x 13.9mm, Bourns CMH322522-180KL sensor inductor with L=18 µH and 33pF 1% COG/NP0 Target: Grounded aluminum plate (176 x 123mm), Channel = Channel 0 (continuous mode) CLKIN = 40MHz, CHx FIN SEL = b10, CHx FREF DIVIDER = b00 0000 0001 CH0 RCOUNT = 0xFFFF, SETTLECOUNT CH0 = 0x0100, DRIVE_CURRENT_CH0 = 0x7800

8.2 Typical Application

The FDC can be used to measure liquid level in non-conductive containers. Due to very high excitation rate capability, the FDC is able to measure soapy water, ink, soap, and other conductive liquids. Capacitive sensors can be attached to the outside of the container or be located remotely from the container, allowing for contactless measurements.

The working principle is based on a ratiometric measurement; [Figure 8-8](#page-41-0) shows a possible system implementation which uses three electrodes. The Level electrode provides a capacitance value proportional to the liquid level. The Reference Environmental electrode and the Reference Liquid electrode are used as references. The Reference Liquid electrode accounts for the liquid dielectric constant and the variation, while the Reference Environmental electrode is used to compensate for any other environmental variations that are not due to the liquid itself. Note that the Reference Environmental electrode and the Reference Liquid electrode are the same physical size (hREF).

For this application, single-ended measurements on the active channels are appropriate, as the tank is grounded. Use Equation to determine the liquid level from the measured capacitances:

$$
Level = h_{ref} \frac{C_{Lev} - C_{Lev}(0)}{C_{RL} - C_{RE}}
$$

where

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- C_{RE} is the capacitance of the Reference Environmental electrode,
- C_{RI} is the capacitance of the Reference Liquid electrode,
- C_{Lev} is the current value of the capacitance measured at the Level electrode sensor,
- $C_{\text{Lev}}(0)$ is the capacitance of the Level electrode when the container is empty, and
- h_{REF} is the height in the desired units of the Container or Liquid Reference electrodes.

The ratio between the capacitance of the level and the reference electrodes allows simple calculation of the liquid level inside the container itself. Very high sensitivity values (that is, many LSB/mm) can be obtained due to the high resolution of the FDC2x1x, even when the sensors are located remotely from the container. Note that this approach assumes that the container has a uniform cross section from top to bottom, so that each incremental increase or decrease in the liquid represents a change in volume that is directly related to the height of the liquid.

8.2.1 Schematic

Figure 8-8. FDC (Liquid Level Measurement)

8.2.2 Design Requirements

Make sure the liquid level measurement are independent of the liquid, which can be achieved using the 3-electrode design described above. Moreover, isolate the sensor from environmental interferences such as a human body, other objects, or EMI.

8.2.3 Detailed Design Procedure

In capacitive sensing systems, the design of the sensor plays an important role in determining system performance and capabilities. In most cases the sensor is simply a metal plate that can be designed on the PCB.

The sensor used in this example is implemented with a two-layer PCB. On the top layer, which faces the tank, there are the 3 electrodes (Reference Environmental, Reference Liquid, and Level) with a ground plane surrounding the electrodes.

Depending on the shape of the container, the FDC can be located on the sensor PCB to minimize the length of the traces between the input channels and the sensors. In case the shape of the container or other mechanical constraints do not allow having the sensors and the FDC on the same PCB, the traces which connect the channels to the sensor need to be shielded with the appropriate shield.

8.2.3.1 Recommended Initial Register Configuration Values

The application requires 100SPS ($T_{SAMPL} = 10$ ms). A sensor with an 18 μ H inductor and a 33pF capacitor is used. Additional pin, trace, and wire capacitance accounts for 20pF, so the total capacitance is 53pF.

Using L and C, $f_{\text{SENSOR}} = 1/2\pi\sqrt{(LC)} = 1/2\pi\sqrt{(18*10^{-6} * 50*10^{-12})} = 5.15\text{MHz}$. This represents the maximum sensor frequency. When the sensor capacitance is added, the frequency decreases.

Using a system controller clock of 40MHz applied to the CLKIN pin allows flexibility for setting the internal clock frequencies. The sensor coils are connected to channel 0 (IN0A and IN0B pins), channel 1 (IN1A and IN1B pins), and channel 2 (IN2A and IN2B pins).

After powering on the FDC, the FDC enters Sleep Mode. Program the registers as follows (example sets registers for channel 0 only; channel 1 and channel 2 registers can use equivalent configuration):

- 1. Set the dividers for channel 0.
	- a. The sensor is in an single-ended configuration, therefore set the sensor frequency select register to 2, which means setting field CH0_FIN_SELto b10.
	- b. The design constraint for f_{REF0} is > 4 \times f_{SENSOR}. To satisfy this constraint, f_{REF0} must be greater than 20.6MHz, so set the reference divider to 1. This is done by setting the CH0_FREF_DIVIDER field to 0x01.
	- c. The combined value for Chan. 0 divider register (0x14) is 0x2001.
- 2. Sensor drive current: to ensure that the oscillation amplitude is between 1.2V and 1.8V, measure the oscillation amplitude on an oscilloscope and adjust the IDRIVE value, or use the integrated FDC GUI feature to determine the optimal setting. In this case, set the IDRIVE value to 15 (decimal), which results in an oscillation amplitude of 1.68V(pk). Set the INIT_DRIVE current field to 0x00. The combined value for the DRIVE_CURRENT_CH0 register (addr 0x1E) is 0x7C00.
- 3. Program the settling time for Channel 0 (see *[Multi-Channel and Single-Channel Operation](#page-12-0)*).
	- a. CHx_SETTLECOUNT > V_{pk} × f_{REFx} × C × π² / (32 × IDRIVE_X) → 7.5, rounded up to 8. To provide margin to account for system tolerances, a higher value of 10 is chosen.
	- b. Program Register 0x10 to a minimum of 10.
	- c. The settle time is: $(10 \times 16)/40,000,000 = 4 \text{ }\mu\text{s}$
	- d. The value for Chan. 0 SETTLECOUNT register (0x10) is 0x000A.
- 4. The channel switching delay is ~1μs for f_{REF} = 40MHz (see *[Multi-Channel and Single-Channel Operation](#page-12-0)*)
- 5. Set the conversion time by the programming the reference count for Channel 0. The budget for the conversion time is : $1/N$ * (T_{SAMPLE} – settling time – channel switching delay) = $1/3$ (10,000 – 4 – 1) = 3.33ms
	- a. To determine the conversion time register value, use the following equation and solve for CH0_RCOUNT: Conversion Time (t_{C0}) = (CH0_RCOUNT×16)/ f_{RFF0} .
	- b. This results in CH0_RCOUNT having a value of 8329 decimal (rounded down). Note that this yields an $ENOB > 13$ bits.
	- c. Set the CH0_RCOUNT register (0x08) to 0x2089.
- 6. Use the default values for the ERROR_CONFIG register (address 0x19). By default, no interrupts are enabled
- 7. Program the MUX_CONFIG register
	- a. Set the AUTOSCAN_EN to b1 bit to enable sequential mode
	- b. Set RR_SEQUENCE to b10 to enable data conversion on three channels (channel 0, channel 1, channel 2)
	- c. Set DEGLITCH to b101 to set the input deglitch filter bandwidth to 10MHz, the lowest setting that exceeds the oscillation tank frequency.

d. The combined value for the MUX_CONFIG register (address 0x1B) is 0xC20D

- 8. Finally, program the CONFIG register as follows:
	- a. Set the ACTIVE CHAN field to b00 to select channel 0.
	- b. Set SLEEP_MODE_EN field to b0 to enable conversion.
	- c. Set SENSOR_ACTIVATE_SEL = b0, for full current drive during sensor activation
	- d. Set the REF_CLK_SRC field to b1 to use the external clock source.
	- e. Set the other fields to their default values.
	- f. The combined value for the CONFIG register (address 0x1A) is 0x1601.

We then read the conversion results for channel 0 to channel 2 every 10ms from register addresses 0x00 to 0x05.

Based on the example configuration above, the following register write sequence is recommended:

8.2.4 Application Curve

A liquid level sensor with 3 electrodes like the one shown in the schematic was connected to the EVM. The plot shows the capacitance measured by Level sensor at different levels of liquid in the tank. The capacitance of the Reference Liquid and Reference Environmental sensors have a steady value because they experience consistent exposure to liquid and air, while the capacitance of the level sensor (Level) increases linearly with the height of the liquid in the tank.

Figure 8-9. Electrode Capacitance vs Liquid Level

8.3 Best Design Practices

- Do leave a small gap between sensor plates in differential configurations. TI recommends a 2mm to 3mm minimum separation.
- The FDC does not support hot-swapping of the sensors. Do not hot-swap sensors, for example by using external multiplexers.

8.4 Power Supply Recommendations

The FDC requires a voltage supply within 2.7V and 3.6V. Multilayer ceramic bypass X7R capacitors of 0.1µF and 1 μF between the VDD and GND pins are recommended. If the supply is located more than a few inches from the FDC, additional bulk capacitance can be required in addition to the ceramic bypass capacitors. An electrolytic capacitor with a value of 10μF is a typical choice.

The optimum placement is closest to the VDD and GND pins of the device. Take care to minimize the loop area formed by the bypass capacitor connection, the VDD pin, and the GND pin of the device. See [Figure 8-10](#page-45-0) and [Figure 8-10](#page-45-0) for a layout example.

8.5 Layout

8.5.1 Layout Guidelines

- Avoid long traces to connect the sensor to the FDC. Short traces reduce parasitic capacitances between sensor inductor and offer higher system performance.
- Systems that require matched channel response need to have matched trace length on all active channels.

8.5.2 Layout Example

[Figure 8-10](#page-45-0) to [Figure 8-13](#page-48-0) show the FDC2114 / FDC2214 evaluation module (EVM) layout.

[FDC2212,](https://www.ti.com/product/FDC2212) [FDC2214](https://www.ti.com/product/FDC2214), [FDC2112](https://www.ti.com/product/FDC2112), [FDC2114](https://www.ti.com/product/FDC2114) [SNOSCZ5B](https://www.ti.com/lit/pdf/SNOSCZ5) – JUNE 2015 – REVISED OCTOBER 2024 **www.ti.com**

Figure 8-10. Example PCB Layout: Top Layer (Signal)

Figure 8-11. Example PCB Layout: Mid-Layer 1 (GND)

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Figure 8-12. Example PCB Layout: Mid-Layer 2 (Power)

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Figure 8-13. Example PCB Layout: Bottom Layer (Signal)

9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com.](https://www.ti.com) Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E™ [support forums](https://e2e.ti.com) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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9.4 Electrostatic Discharge Caution

This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

[TI Glossary](https://www.ti.com/lit/pdf/SLYZ022) This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

PACKAGE OPTION ADDENDUM

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF FDC2112, FDC2112-Q1, FDC2114, FDC2114-Q1, FDC2212, FDC2212-Q1, FDC2214, FDC2214-Q1 :

• Catalog : [FDC2112,](http://focus.ti.com/docs/prod/folders/print/fdc2112.html) [FDC2114,](http://focus.ti.com/docs/prod/folders/print/fdc2114.html) [FDC2212](http://focus.ti.com/docs/prod/folders/print/fdc2212.html), [FDC2214](http://focus.ti.com/docs/prod/folders/print/fdc2214.html)

• Automotive : [FDC2112-Q1,](http://focus.ti.com/docs/prod/folders/print/fdc2112-q1.html) [FDC2114-Q1,](http://focus.ti.com/docs/prod/folders/print/fdc2114-q1.html) [FDC2212-Q1,](http://focus.ti.com/docs/prod/folders/print/fdc2212-q1.html) [FDC2214-Q1](http://focus.ti.com/docs/prod/folders/print/fdc2214-q1.html)

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

TEXAS

TAPE AND REEL INFORMATION

ISTRUMENTS

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

PACKAGE MATERIALS INFORMATION

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PACKAGE OUTLINE

DNT0012B WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

2. This drawing is subject to change without notice.

3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

DNT0012B WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD

NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

EXAMPLE STENCIL DESIGN

DNT0012B WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD

NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

PACKAGE OUTLINE

RGH0016A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.
- 3. The package thermal pad must be soldered to the printed circuit board for optimal thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

RGH0016A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

RGH0016A WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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